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# Optics and photonics — Optical materials and components — Test method for homogeneity of optical glasses by laser interferometry

*Optique et photonique — Matériaux et composants optiques  
— Méthode d'essai d'homogénéité des verres optiques par  
interférométrie laser*



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CH-1214 Vernier, Geneva  
Phone: +41 22 749 01 11  
Email: [copyright@iso.org](mailto:copyright@iso.org)  
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## Foreword

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The procedures used to develop this document and those intended for its further maintenance are described in the ISO/IEC Directives, Part 1. In particular, the different approval criteria needed for the different types of ISO documents should be noted. This document was drafted in accordance with the editorial rules of the ISO/IEC Directives, Part 2 (see [www.iso.org/directives](http://www.iso.org/directives)).

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This document was prepared by Technical Committee ISO/TC 172, *Optics and Photonics*, Subcommittee SC 3, *Optical materials and components*.

This second edition cancels and replaces the first edition (ISO 17411:2014), which has been technically revised.

The main changes are as follows:

- the PHom method was added;
- the FT-PSI method and the SCI method were added;
- the linear change of the refractive index is described as an evaluation target.

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